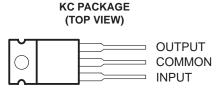
- ±1% Output Tolerance at 25°C
- ±2% Output Tolerance Over Full Operating Range
- Thermal Shutdown

- Internal Short-Circuit Current Limiting
- Pinout Identical to μA7800 Series
- Improved Version of μA7800 Series

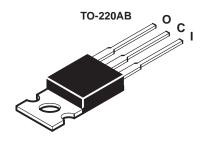
## description

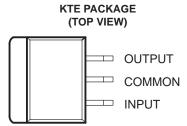
Each fixed-voltage precision regulator in the TL780 series is capable of supplying 1.5 A of load current. A unique temperature-compensation technique, coupled with an internally trimmed band-gap reference, has resulted in improved accuracy when compared to other three-terminal regulators. Advanced layout techniques provide excellent line, load, and thermal regulation. The internal current-limiting and thermal-shutdown features make the devices essentially immune to overload.

The TL780-xxC series regulators are characterized for operation over the virtual junction temperature range of 0°C to 125°C.

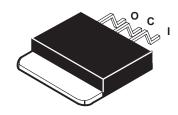


The COMMON terminal is in electrical contact with the mounting base.





The COMMON terminal is in electrical contact with the mounting base.



#### **AVAILABLE OPTIONS**

		PACKAGEI	CHIP	
TJ	V <sub>O</sub> TYP (V)	I DEAT SINK MOUNTED I		FORM (Y)
	5	TL780-05CKC	TL780-05CKTE	TL780-05Y
0°C to 125°C	12	TL780-12CKC	TL780-12CKTE	TL780-12Y
	15	TL780-15CKC	TL780-15CKTE	TL780-15Y

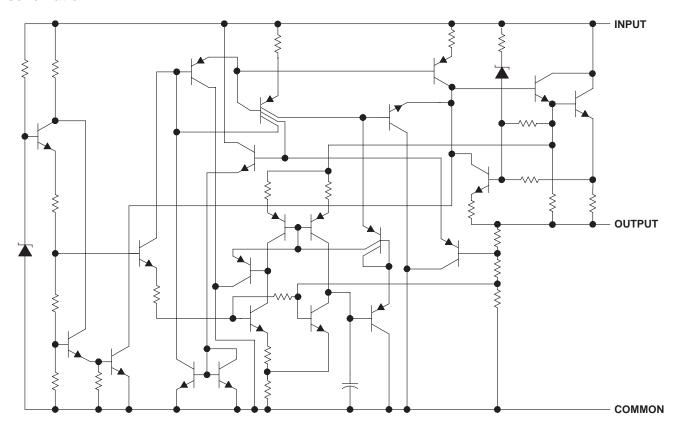
The KTE package is available taped and reeled. Add the suffix R to the device type (e.g., TL780-05CKTER). Chip forms are tested at 25°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



## schematic



## absolute maximum ratings over operating temperature range (unless otherwise noted)†

Input voltage, V <sub>I</sub>	35 V
Package thermal impedance, θ <sub>IA</sub> (see Notes 1 and 2)	: KC package 22°C/W
, <b>3,</b> , ,	KTE package 23°C/W
Operating free-air, TA; case, TC; or virtual junction, TJ,	temperature range 0°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10	seconds 260°C
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## recommended operating conditions

		MIN	MAX	UNIT
	TL780-05C	7	25	
Input voltage, V <sub>I</sub>	TL780-12C	14.5	30	V
	TL780-15C	17.5	30	
Output current, IO				А
Operating virtual junction temperature, TJ				°C

## electrical characteristics at specified virtual junction temperature, $V_I = 10 \text{ V}$ , $I_O = 500 \text{ mA}$ (unless otherwise noted)

DADAMETED	TEST CONDI	TEST CONDITIONS		TL780-05C			UNIT	
PARAMETER	IESI CONDI			MIN	TYP	MAX	UNIT	
Output voltage	$I_O = 5$ mA to 1 A,	$I_O = 5$ mA to 1 A, $P \le 15$ W, $V_I = 7$ V to 20 V	25°C	4.95	5	5.05	V	
Output voltage	$V_{I} = 7 \text{ V to } 20 \text{ V}$		0°C to 125°C	4.9		5.1	٧	
Input voltage regulation	V <sub>I</sub> = 7 V to 25 V		2500		0.5	5	mV	
	V <sub>I</sub> = 8 V to 12 V		25°C		0.5	5		
Ripple rejection	V <sub>I</sub> = 8 V to 18 V,	f = 120 Hz	0°C to 125°C	70	85		dB	
Output voltage regulation	I <sub>O</sub> = 5 mA to 1.5 A		25°C		4	25	\/	
	$I_O = 250 \text{ mA to } 750$	I <sub>O</sub> = 250 mA to 750 mA			1.5	15	m∨	
Output resistance	f = 1 kHz		0°C to 125°C		0.0035		W	
Temperature coefficient of output voltage	I <sub>O</sub> = 5 mA		0°C to 125°C		0.25		mV/°C	
Output noise voltage	f = 10 Hz to 100 kHz		25°C		75		μV	
Dropout voltage	I <sub>O</sub> = 1 A		25°C		2		V	
Input bias current			25°C		5	8	mA	
Land bin a summer of the same	V <sub>I</sub> = 7 V to 25 V	V <sub>I</sub> = 7 V to 25 V			0.7	1.3	^	
Input bias-current change	$I_O = 5 \text{ mA to } 1 \text{ A}$		0°C to 125°C 0.003		0.003	0.5	mA	
Short-circuit output current			25°C		750		mA	
Peak output current			25°C		2.2		А	

<sup>‡</sup> Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.22-μF capacitor across the output.



NOTES: 1. Maximum power dissipation is a function of  $T_J(max)$ ,  $\theta_{JA}$ , and  $T_A$ . The maximum allowable power dissipation at any allowable ambient temperature is  $P_D = (T_J(max) - T_A)/\theta_{JA}$ . Operating at the absolute maximum  $T_J$  of 150°C can impact reliability. Due to variations in individual device electrical characteristics and thermal resistance, the built-in thermal overload protection may be activated at power levels slightly above or below the rated dissipation.

<sup>2.</sup> The package thermal impedance is calculated in accordance with JESD 51.

## electrical characteristics at specified virtual junction temperature, $V_I$ = 19 V, $I_O$ = 500 mA (unless otherwise noted)

PARAMETER	TEST CONDITIONS		- +	TL780-12C			UNIT	
PARAMETER			TJ <sup>†</sup>	MIN	TYP	MAX	ONIT	
Output voltage	$I_0 = 5 \text{ mA to 1 A},  P \le$	P ≤ 15 W,	25°C	11.88	12	12.12	V	
Output voltage	V <sub>I</sub> = 14.5 V to 27 V		0°C to 125°C	11.76		12.24	V	
Input voltage regulation	V <sub>I</sub> = 14.5 V to 30 V		25°C		1.2	12	\/	
Input voltage regulation	V <sub>I</sub> = 16 V to 22 V		25 C		1.2	12	m∨	
Ripple rejection	$V_I = 15 \text{ V to } 25 \text{ V}, \qquad f = 10 \text{ V}$	120 Hz	0°C to 125°C	65	80		dB	
Output voltage regulation	I <sub>O</sub> = 5 mA to 1.5 A		25°C		6.5	60	mV	
	I <sub>O</sub> = 250 mA to 750 mA		25 C		2.5	36		
Output resistance	f = 1 kHz		0°C to 125°C		0.0035		W	
Temperature coefficient of output voltage	I <sub>O</sub> = 5 mA		0°C to 125°C		0.6		mV/°C	
Output noise voltage	f = 10 Hz to 100 kHz		25°C		180		μV	
Dropout voltage	I <sub>O</sub> = 1 A		25°C		2		V	
Input bias current			25°C		5.5	8	mA	
Input biog gurrent change	V <sub>I</sub> = 14.5 V to 30 V I <sub>O</sub> = 5 mA to 1 A		0°C to 125°C		0.4	1.3	^	
Input bias-current change			0.0 10 125.0		0.03	0.5	mA	
Short-circuit output current			25°C		350		mA	
Peak output current			25°C		2.2		Α	

<sup>†</sup> Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-µF capacitor across the input and a 0.22-µF capacitor across the output.

# electrical characteristics at specified virtual junction temperature, $V_I$ = 23 V, $I_O$ = 500 mA (unless otherwise noted)

PARAMETER	TEST CONDITIONS	_ +	TL780-15C			UNIT	
PARAMETER	TEST CONDITIONS	T <sub>J</sub> †	MIN	TYP	MAX	ONT	
Output voltage	$I_{O} = 5 \text{ mA to 1 A}, \qquad P \le 15 \text{ W},$	25°C	14.85	15	15.15	V	
Output voltage	V <sub>I</sub> = 17.5 V to 30 V	0°C to 125°C	14.7		15.3	V	
Input voltage regulation	V <sub>I</sub> = 17.5 V to 30 V	25°C		1.5	15	>/	
input voitage regulation	V <sub>I</sub> = 20 V to 26 V	25 C		1.5	15	m∨	
Ripple rejection	$V_I = 18.5 \text{ V to } 28.5 \text{ V},  f = 120 \text{ Hz}$	0°C to 125°C	60	75		dB	
Output voltage regulation	$I_O = 5 \text{ mA to } 1.5 \text{ A}$	25°C		7	75	mV	
	I <sub>O</sub> = 250 mA to 750 mA	25 C		2.5	45		
Output resistance	f = 1 kHz	0°C to 125°C		0.0035		W	
Temperature coefficient of output voltage	$I_O = 5 \text{ mA}$	0°C to 125°C		0.62		mV/°C	
Output noise voltage	f = 10 Hz to 100 kHz	25°C		225		μV	
Dropout voltage	I <sub>O</sub> = 1 A	25°C		2		V	
Input bias current		25°C		5.5	8	mA	
Input bias-current change	V <sub>I</sub> = 17.5 V to 30 V	0°C to 125°C		0.4	1.3	mA	
input bias-current change	$I_O = 5$ mA to 1 A			0.02	0.5	111/4	
Short-circuit output current		25°C		230		mA	
Peak output current		25°C		2.2		Α	

<sup>†</sup> Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-µF capacitor across the input and a 0.22-µF capacitor across the output.



## electrical characteristics, $V_I$ = 10 V, $I_O$ = 500 mA, $T_J$ = 25°C (unless otherwise noted)

DADAMETED		TL780-05Y			UNIT	
PARAMETER	TEST CONDITIONS†	MIN	TYP	MAX	UNII	
Output voltage	$I_{O} = 5 \text{ mA to 1 A}, \qquad P \le 15 \text{ W}$		5		V	
	V <sub>I</sub> = 7 V to 25 V	0.5			mV	
Input voltage regulation	V <sub>I</sub> = 8 V to 12 V		0.5		mv	
Outside of the second of the	I <sub>O</sub> = 5 mA to 1.5 A	4			mV	
Output voltage regulation	I <sub>O</sub> = 250 mA to 750 mA		1.5		IIIV	
Output noise voltage	f = 10 Hz to 100 kHz		75		μV	
Dropout voltage	I <sub>O</sub> = 1 A		2		V	
Input bias current			5		mA	
Short-circuit output current			750		mA	
Peak output current			2.2		Α	

<sup>†</sup> Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.22-μF capacitor across the output.

## electrical characteristics, $V_I$ = 19 V, $I_O$ = 500 mA, $T_J$ = 25°C (unless otherwise noted)

PARAMETER	TEST SOMBITIONS!	TL780-12Y			UNIT	
PARAINETER	TEST CONDITIONS†		TYP	MAX	UNIT	
Output voltage	$I_O = 5 \text{ mA to 1 A}, \qquad P \le 15 \text{ W}$		12		V	
land valle on a sulption	$V_{I} = 14.5 \text{ V to } 30 \text{ V}$		1.2		mV	
Input voltage regulation	V <sub>I</sub> = 16 V to 22 V		1.2		IIIV	
Output valte as negulation	$I_{O} = 5 \text{ mA to } 1.5 \text{ A}$		6.5		mV	
Output voltage regulation	$I_O = 250 \text{ mA to } 750 \text{ mA}$		2.5			
Output noise voltage	f = 10 Hz to 100 kHz		180		μV	
Dropout voltage	I <sub>O</sub> = 1 A		2		V	
Input bias current			5.5		mA	
Short-circuit output current			350		mA	
Peak output current			2.2		А	

<sup>†</sup> Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.22-μF capacitor across the output.

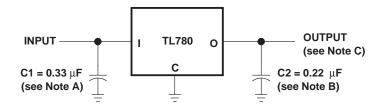


## electrical characteristics, $V_I$ = 23 V, $I_O$ = 500 mA, $T_J$ = 25°C (unless otherwise noted)

PARAMETER		TL780-15Y	UNIT	
PARAMETER	TEST CONDITIONS†	MIN TYP MAX	IIII	
Output voltage	$I_O = 5 \text{ mA to 1 A}, \qquad P \le 15 \text{ W}$	15	V	
Input voltage regulation	V <sub>I</sub> = 17.5 V to 30 V	1.5	mV	
Input voltage regulation	V <sub>I</sub> = 20 V to 26 V	1.5	IIIV	
Output voltage regulation	I <sub>O</sub> = 5 mA to 1.5 A	7	mV	
Output voltage regulation	I <sub>O</sub> = 250 mA to 750 mA	2.5	IIIV	
Output resistance	f = 1 kHz	0.0035	W	
Output noise voltage	f = 10 Hz to 100 kHz	225	μV	
Dropout voltage	I <sub>O</sub> = 1 A	2	V	
Input bias current		5.5	mA	
Short-circuit output current		230	mA	
Peak output current		2.2	Α	

<sup>†</sup> Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-µF capacitor across the input and a 0.22-µF capacitor across the output.

### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C1 is required when the regulator is far from the power-supply filter.

- B. C2 is not required for stability; however, transient response is improved.
- C. Permanent damage can occur when OUTPUT is pulled below ground.

Figure 1. Test Circuit



#### **APPLICATION INFORMATION**

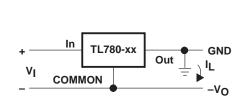


Figure 2. Positive Regulator in Negative Configuration (V<sub>I</sub> Must Float)

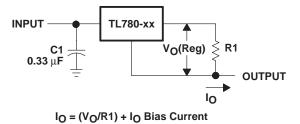


Figure 3. Current Regulator

## operation with a load common to a voltage of opposite polarity

In many cases, a regulator powers a load that is not connected to ground but, instead, is connected to a voltage source of opposite polarity (e.g., operational amplifiers, level-shifting circuits, etc.). In these cases, a clamp diode should be connected to the regulator output as shown in Figure 4. This protects the regulator from output polarity reversals during startup and short-circuit operation.

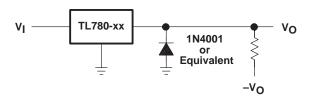


Figure 4. Output Polarity-Reversal-Protection Circuit

## reverse-bias protection

Occasionally, the input voltage to the regulator can collapse faster than the output voltage. This, for example, could occur when the input supply is crowbarred during an output overvoltage condition. If the output voltage is greater than approximately 7 V, the emitter-base junction of the series pass element (internal or external) could break down and be damaged. To prevent this, a diode shunt can be employed, as shown in Figure 5.

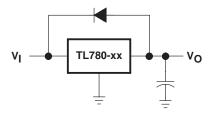


Figure 5. Reverse-Bias-Protection Circuit

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